AMENDMENTS TO THE SPECIFICATION

Please amend the specification as indicated hereafter. It is believed that the following amendments and additions add no new matter to the present application.

Please replace paragraph [00014] with the following amended paragraph:

[00014]   The scan converter 106 formats the test data 104 and 105 to produce formatted test data 107 and 108, respectively, that are subsequently provided to a DUT tester 109. The formatted test data 108 has different properties than the formatted test data 107, including, for example, different timing complexity, vector data volume, and repetitiveness, among others. The DUT tester 109 includes resources 110 coupled to scan-pins 113 of a DUT 112, and resources 111 coupled to non-scan-pins 114 of the DUT 112. The resources 110 may operate in a different timing domain than the resources 111. For example, the resources 110 may include processors running at a first clock speed, and the resources 111 may include processors running at a second clock speed. The resources 110 receive the formatted test data 107 and provide or receive corresponding test signals 115 to or from scan-pins 113. On the other hand, the resources 111 receive the formatted test data 108 and provide or receive corresponding test signals 117 to or from non-scan-pins 114.